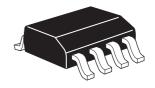


ZXMN6A25DN8 Dual 60V SO8 N-channel enhancement mode MOSFET

Summary

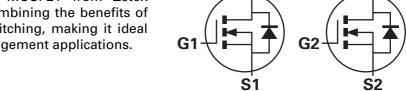
V _{(BR)DSS}	$R_{DS(on)}$ (Ω)	I _D (A)
60	0.050 @ V _{GS} = 10V	5
00	0.070 @ V _{GS} = 4.5V	4.2



D2

Description

This new generation trench MOSFET from Zetex features a unique structure combining the benefits of low on-resistance and fast switching, making it ideal for high efficiency power management applications.



D1

Features

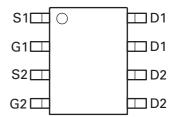
- · Low on-resistance
- · Fast switching speed
- · Low gate drive
- · Low profile SO8 package

Applications

- · DC DC converters
- · Power management functions
- Motor control

Ordering information

Device	Reel (inches)	Tape width (mm)	Quantity per reel
ZXMN6A25DN8TA	7	12	500
ZXMN6A25DN8TC	13	12	2500



Pin out - top view

Device marking

ZXMN 6A25D

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain-source voltage	V_{DSS}	60	V
Gate-source voltage	V _{GS}	±20	V
Continuous drain current @V _{GS} =10V; T _{amb} =25°C ^{(b) (d)}		5	А
@V _{GS} =10V; T _{amb} =70°C ^{(b) (d)}	I _D	4	Α
@V _{GS} =10V; T _{amb} =25°C ^{(a) (d)}		3.8	Α
Pulsed drain current ^(c)	I _{DM}	24	Α
Continuous source current (body diode) ^(b)	I _S	3.4	Α
Pulsed source current (body diode) ^(c)	I _{SM}	24	Α
Power dissipation at T _{amb} =25°C ^{(a) (d)}	P _D	1.25	W
Linear derating factor		10	mW/°C
Power dissipation at T _{amb} =25°C ^{(a) (e)}	P _D	1.8	W
Linear derating factor		14	mW/°C
Power dissipation at T _{amb} =25°C ^{(b) (d)}	P _D	2.1	W
Linear derating factor		17	mW/°C
Operating and storage temperature range	T _j :T _{stg}	-55 to +150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^{(a) (d)}	$R_{\Theta JA}$	100	°C/W
Junction to ambient ^{(a) (e)}	$R_{\Theta JA}$	70	°C/W
Junction to ambient ^{(b) (d)}	$R_{\Theta JA}$	60	°C/W

NOTES:

⁽a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

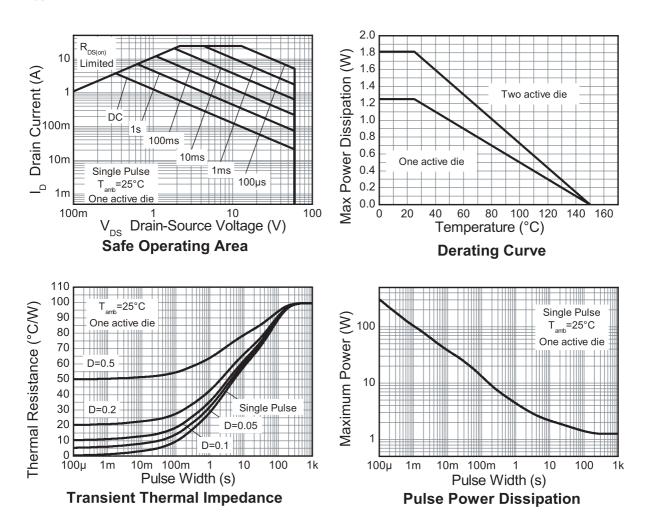
⁽b) For a device surface mounted on FR4 PCB measured at t \leq 10 sec.

⁽c) Repetitive rating 25mm x 25mm FR4 PCB, D=0.02, pulse width= $300\mu s$ - pulse width limited by maximum junction temperature.

⁽d) For a dual device with one active die.

⁽e) For a device with two active die running at equal power.

Typical characteristics



Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static			•	•		
Drain-source breakdown voltage	V _{(BR)DSS}	60			V	I _D =250μA, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}			1.0	mA	V _{DS} =60V, V _{GS} =0V
Gate-body leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V
Gate-source threshold voltage	V _{GS(th)}	1.0			V	$I_D=250\mu A$, $V_{DS}=V_{GS}$
Static drain-source on-state	R _{DS(on)}			0.050	Ω	V _{GS} =10V, I _D =3.6A
resistance (*)				0.070	Ω	V _{GS} =4.5V, I _D =3A
Forward transconductance (*)(‡)	9 _{fs}		10.2		S	V _{DS} =15V,I _D =4.5A
Dynamic ^(‡)			•	•		
Input capacitance	C _{iss}		1063		pF), oo,
Output capacitance	C _{oss}		104		pF	V _{DS} =30V, V _{GS} =0V,f=1MHz
Reverse transfer capacitance	C _{rss}		64		pF	VGS-0 V,1- 11V1112
Switching (†) (‡)			•			
Turn-on delay time	t _{d(on)}		3.8		ns	
Rise time	t _r		4.0		ns	V _{DD} =30V, I _D =1A
Turn-off delay time	t _{d(off)}		26.2		ns	RG≅6.0Ω, V _{GS} =10V
Fall Time	t _f		10.6		ns	
Gate charge	Q_g		11.0		nC	V_{DS} =30V, V_{GS} =5V, I_{D} =4.5A
Total gate charge	Q_g		20.4		nC	V _{DS} =30V,V _{GS} =10V,
Gate-source charge	Q_{gs}		4.1		nC	I _D =4.5A
Gate-drain charge	Q_{gd}		5.1		nC	
Source-drain diode	ı		ı	ı		
Diode Forward Voltage ^(*)	V_{SD}		0.85	0.95	V	T _J =25°C, I _S =5.5A,V _{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		22.0		ns	T _J =25°C, I _F =2.2A,
Reverse recovery charge ^(‡)	Q _{rr}		21.4		nC	di/dt= 100A/μs

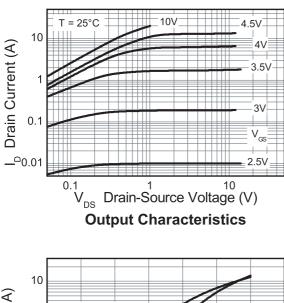
NOTES:

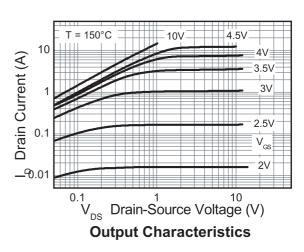
^(*) Measured under pulsed conditions. Width=300 $\mu s.$ Duty cycle $\leq 2\%$.

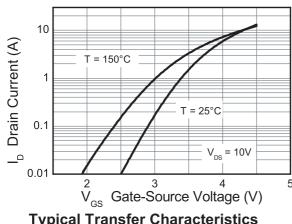
^(†) Switching characteristics are independent of operating junction temperature.

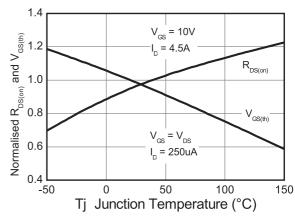
^(‡) For design aid only, not subject to production testing.

Typical characteristics

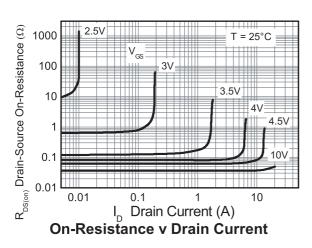




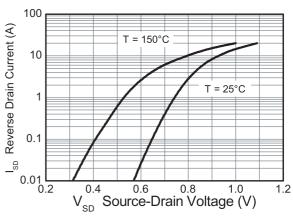




Typical Transfer Characteristics

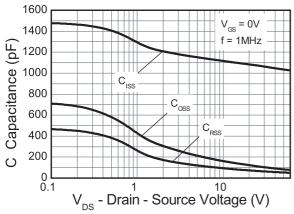


Normalised Curves v Temperature

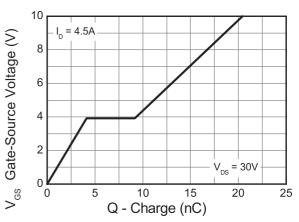


Source-Drain Diode Forward Voltage

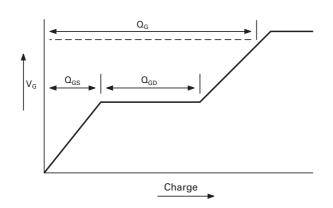
Typical characteristics



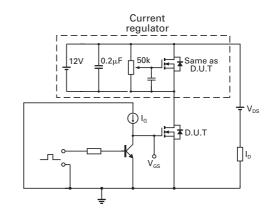
Capacitance v Drain-Source Voltage



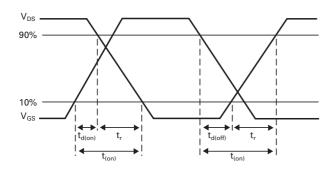
Gate-Source Voltage v Gate Charge



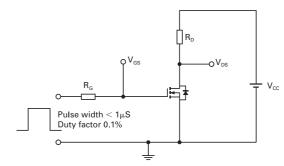
Basic gate charge waveform



Gate charge test circuit

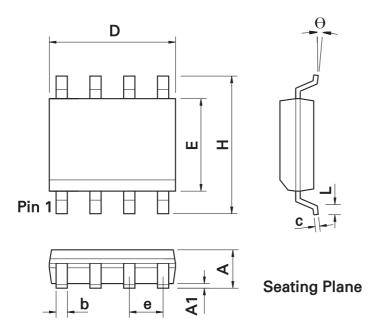


Switching time waveforms



Switching time test circuit

Package outline - SO8



DIM	Inc	hes	Millin	neters	DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	0.053	0.069	1.35	1.75	е	0.050	BSC	1.27	BSC
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
Н	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
Е	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

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Europe	Americas	Asia Pacific	Corporate Headquarters
Zetex GmbH Kustermann-park Balanstraße 59	Zetex Inc 700 Veterans Memorial Highway Hauppauge, NY 11788	Zetex (Asia Ltd) 3701-04 Metroplaza Tower 1 Hing Fong Road, Kwai Fong	Zetex Semiconductors plc Zetex Technology Park, Chadderton Oldham, OL9 9LL
D-81541 München Germany	USA	Hong Kong	United Kingdom
Telefon: (49) 89 45 49 49 0 Fax: (49) 89 45 49 49 49 europe.sales@zetex.com	Telephone: (1) 631 360 2222 Fax: (1) 631 360 8222 usa.sales@zetex.com	Telephone: (852) 26100 611 Fax: (852) 24250 494 asia.sales@zetex.com	Telephone: (44) 161 622 4444 Fax: (44) 161 622 4446 hq@zetex.com
			dc

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